

Search Notes

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Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under
Reexamination

FONG ET AL.

Art Unit

2636

SEARCHED

Class	Subclass	Date	Examiner
340	573.4	6/8/2005	JAT
	539.13	6/8/2005	JAT
	539.15	6/8/2005	JAT
	539.21	6/8/2005	JAT
	539.23	6/8/2005	JAT
	573.1	6/8/2005	JAT
	573.3	6/8/2005	JAT
455	421	6/8/2005	JAT
	134	6/8/2005	JAT
	457	6/8/2005	JAT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner